INFORMATION DISCLOSURE STATEMENT

PTO-1449

ATTY. DOCKET NO. SERIAL NO. 26822-0002 P2 10/092,936

APPLICANTS: RONG, Chang-Liang, et al.

U.S. PATENT DOCUMENTS NAME CLASS SUBCLASS FILING DATE NAME CLASS SUBCLASS FILING DATE T.T. 5,177,476				FILING DATE: 03/06/2002		GRC	OUP: 2873				
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	PTO-1449	[APPLICANTS: RONG, Chang-Liang, et al.						
			FILING DATE: 03/06/2002		GRO	OUP: 2873			
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^{*}If an asterisk is placed beside the reference number, a copy is not provided because the reference was previously cited by or submitted to the PTO in a prior application that is identical in the statement and relied upon for an earlier filing date under 35 U.S.C. §120. 37 C.F.R. §1.98 (d).

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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

^{&#}x27;See English counterparts US Patent No. 6,512,626 or Canadian Patent Application No. 2,340,683. Applicant would be happy to obtain a direct translation of the document if desired.

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SHEET 1 OF 1

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		ITATION			26822-0002P2 10/092,936															
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